PCN Number:			20170207002					F	PCN Date: F		Feb 13, 2017	
Title:Qualification of APackage Devices					KOR P3	as	Addition	al Assembly and Tes	st Si	te for S	Select	VSON-CLIP
Customer Contact: PCN Man				anager Dept: Quality Services								
Proposed 1 st Shi			p Date: May 13,		3, 2	2017	Estimated Sample Date provided at Availability: sample request					
Change Type:												
\boxtimes	Assembly Site		e 🗌			Design	Design		Wafe	r Bump	o Site	
Assembly Pro			cess		Data Sl	neet		Wafe	r Bump	o Material		
Assembly Mat			terials				Part nu	Part number change		Wafe	r Bump	o Process
Mechanical Sp			ecification 🛛 🛛		Test Site			Wafe	r Fab S	Site		
Packing/Shippir			oing/l	Labelir	ng		Test Pr	ocess 🗌 Wafer		r Fab N	faterials	
								Wafe	r Fab F	Process		
PCN Details												

Description of Change:

Texas Instruments Incorporated is announcing the qualification of AMKOR P3 as Additional Assembly and Test Site for select devices listed in the "Product Affected" Section. Current assembly sites and Material differences are as follows.

Assembly Site	Assembly Site Origin	Assembly Country Code	Assembly Site City	
TI Clark	QAB	PHL	Angeles City, Pampanga	
Amkor P3	AP3	PHL	Biñan, Laguna	

Material Differences:

	TI Clark	AMKOR P3
Mold compound	4208625	101390791
Lead finish	NiPdAu	Matte Sn

Test coverage, insertions, conditions will remain consistent with current testing and verified with test MQ.

Reason for Change:

Continuity of supply.

Anticipated impact on Form, Fit, Function, Quality or Reliability (positive / negative):

None

Anticipated impact on Material Declaration

No Impact to the Material Declaration	Material Declarations or Product Content reports are driven from production data and will be available following the production release. Upon production release the revised reports can be obtained from the <u>TI ECO website</u> .
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Changes to product identification resulting from this PCN:

ssembly Site:				Т				
FI-CLARK	Assembly Site Origin (22L) ASO: QAB	ECAT: E4	_				
AMKOR P3	Assembly Site Origin (22L) ASO: AP3	ECAT: E3					
TEXAS	B	(1P) \$N74		AT: E4 = NiPdAu AT: E3 = Matte Sn				
MADE IN: Malaysia G4 (101) 3 1 4 1 (0) 2000 (D) 0226								
THUE IN. Marays.		E (Q) 2000	(D) 0336					
2DC: 2Q:		⊈ (Q)2000 ≅ (31T)LOT:	(D) ()336 3959047MLA					
2DC: 20: MSL`2 /260C/1 YE MSL 1 /235C/UNL]	AR SEAL DT	(31T)LOT: (4W) TKY(1		2				
2DC: 2Q: MSL 2 /260C/1 YI MSL 1 /235C/UNL] OPT: TTEM.	AR SEAL DT IM 03/29/04	(31T)LOT: (4W)TKY(1 (P) (2P) REV:	3959047MLA T) 7523483S1 (V) 0033317					
2DC: 2Q: MSL 2 /260C/1 YI MSL 1 /235C/UNL] OPT: TTEM.	AR SEAL DT IM 03/29/04	(31T)LOT: (4W)TKY(1	3959047MLA T) 7523483S1 (V) 0033317 E (21L) CC0:USA					
2DC: 2Q: MSL 2 /260C/1 YI MSL 1 /235C/UNL] OPT: TTEM.	AR SEAL DT IM 03/29/04	(31T)LOT: (4W)TKY(1 (P) (2P) REV: (20L) CS0:SH	3959047MLA T) 7523483S1 (V) 0033317 E (21L) CC0:USA					
2DC: 20: MSL 2 /260C/1 YE MSL 1 /235C/UNL OPT: ITEM: LBL: 5A (L)	AR SEAL DT IM 03/29/04	(31T)LOT: (4W)TKY(1 (P) (2P)REV: (20L)CS0:SH (22L)AS0:ML	3959047MLA T) 7523483S1 (V) 0033317 E (21L) CC0:USA					
2DC: 20: MSL 2 /260C/1 YE MSL 1 /235C/UNL) OPT: ITEM: LBL: 5A (L) SSEMBLY SITE (AR SEAL DT 103/29/04 T0:1750 CODES: TI-CLARK = I, AP3	(31T)LOT: (4W)TKY(1 (P) (2P)REV: (20L)CS0:SH (22L)AS0:ML	3959047MLA T) 7523483S1 (V) 0033317 E (21L) CC0:USA					
2DC: 20: MSL 2 /260C/1 YE MSL 1 /235C/UNL OPT: ITEM: LBL: 5A (L)	AR SEAL DT 103/29/04 T0:1750 CODES: TI-CLARK = I, AP3	(31T)LOT: (4W)TKY(1 (P) (2P)REV: (20L)CS0:SH (22L)AS0:ML	3959047MLA T) 7523483S1 (V) 0033317 E (21L) CC0:USA A (23L) AC0: MYS					

Qualification Report Phase 7 Power Block Qual in Amkor P3: CSD87333Q3D, CSD87334Q3D, CSD87335Q3D

Approve Date 06-February-2017

Product Attributes

Attributes	Qual Device: CSD87333Q3D	Qual Device: CSD87334Q3D	Qual Device: CSD87335Q3D				
Assembly Site	AMKOR P3 A/T PHIL	AMKOR P3 A/T PHIL	AMKOR P3 A/T PHIL				
Package Family	DQZ	DQZ	DQZ				
Flammability Rating	UL 94 V-0	UL 94 V-0	UL 94 V-0				
Wafer Fab Supplier	CFAB	CFAB	CFAB				
Wafer Fab Process	NEXFET-LV 30N10	NEXFET-LV 30N10	NEXFET-LV 30N10				

- QBS: Qual By Similarity

- Qual Device CSD87333Q3D is qualified at LEVEL1-260C

- Qual Device CSD87335Q3D is qualified at LEVEL1-260C

- Qual Device CSD87334Q3D is qualified at LEVEL1-260C

- Device CSD87333Q3D contains multiple dies.

- Device CSD87334Q3D contains multiple dies.

- Device CSD87335Q3D contains multiple dies

Qualification Results

Data Displayed as: Number of lots / Total sample size / Total failed

Туре	Test Name / Condition	Duration	Qual Device: CSD87333Q3D	Qual Device: CSD87334Q3D	Qual Device: CSD87335Q3D
MQ	Manufacturability (Assembly)	(per mfg. Site specification)	3/1/0 - Pass	3/1/0 - Pass	3/1/0 - Pass
PC	Preconditioning	(per the appropriate pkg level)	-	3/462/0	3/462/0
TC	**T/C -40C/125C	-40C/+125C (500,1000 Cycles)	-	3/231/0	3/231/0
тс	**T/C -55C/125C	-55C/+125C (500,1000 Cycles)	-	3/231/0	3/231/0

** Preconditioning was performed for Temperature Cycle as applicable

- The following are equivalent Temp Cycle options per JESD47 : -55C/125C/700 Cycles and -65C/150C/500 Cycles Quality and Environmental data is available at TI's external Web site: http://www.ti.com/

Green/Pb-free Status:

Qualified Pb-Free(SMT) and Green

For questions regarding this notice, e-mails can be sent to the regional contacts shown below or your local Field Sales Representative.

Location	E-Mail
USA	PCNAmericasContact@list.ti.com
Europe	PCNEuropeContact@list.ti.com
Asia Pacific	PCNAsiaContact@list.ti.com
Japan	PCNJapanContact@list.ti.com